RF SAFETY LAB
A NEXT GENERATION TEST LABORATORY™

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PART 0 RF EXPOSURE REPORT

FCC ID:	**A3LSMF976B**
Model (s):	SM-F976B
Device Type:	Portable Handset
Report Issue Date:	July 22, 2026

Samsung Electronics Co., Ltd.
129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea

Class II Permissive Change

The measurement evaluations presented in this report are based on the maximum performance of the tested device(s), which has been shown to be capable of compliance for localized specific absorption rate (SAR) for uncontrolled environment/ general population exposure federal limits in 47CFR § 1.1310 and has been tested in accordance with the measurement procedures specified within this report.

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ANAB ANSI National Accreditation Board ACCREDITED ISO/IEC 17025 TESTING LABORATORY

BLOCKCHAIN VERIFIED

Steve Liu
President

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1. DUT Specifics

1.1. Device under Test

The device under test is a wireless device, evaluated for the technologies/exposure conditions listed in Part 1 RF Exposure report under Class II permissive change as described in FCC change document. This device uses the Qualcomm® Gen2 Smart Transmit feature to control and manage transmitting at all times for WWAN/WLAN/BT operations. Additionally, this device supports NFC/WPC/UWB technologies, but the output power of these modes are not controlled by the Smart Transmit algorithm.

RF Exposure Part 1 report in this report refers to report SN: 2026.036.01

1.2. Time-Averaging Algorithm for RF Exposure Compliance

This device is enabled with the Qualcomm® Smart Transmit Gen2 feature. This feature implements a time-averaging algorithm in real time to control and manage transmitting power and ensure the time-averaged RF exposure is in compliance with FCC requirements all the time.

This Part 0 report shows SAR characterization of Smart Transmit enabled radios affected by Class II permissive change. Characterization is achieved by determining P_{Limit} for those radios that corresponds to the exposure design targets after accounting for all device design related uncertainty. The SAR characterization is denoted as SAR Char in this report.

1.3. Nomenclature

Technology	Term	Description
Sub6 WWAN/WLAN/BT	P_{limit}	Power level that corresponds to the exposure design target (*SAR_design_target*) after accounting for all device design related uncertainties
	P_{max}	Maximum tune-up output power
	SAR_design_target	Target SAR level < FCC SAR limit after accounting for all device design related uncertainties
	SAR Char	Table containing P_{limit} for all technologies and bands

2. SAR Characterization

2.1. DSI and SAR Determination

This device uses different Device State Index (DSI) to configure different time averaged power levels based on certain exposure scenarios. Depending on the detection scheme implemented in the smartphone, the worst-case SAR was determined by measurements for the relevant exposure conditions for that DSI. Detailed descriptions of the detection mechanisms are included in the operational description.

When 1g SAR and 10g SAR exposure comparison is needed, the worst-case was determined from SAR normalized to 1g or 10g SAR limit.

The device state index (DSI) condition used in Table below represents different exposure scenarios being affected by the Class II permissive change.

Table 2-1

Scenario	Description	SAR Test Cases
Body-worn (DSI = 0)	_ DUT Configuration is Folder Open _ Device being used with a body-worn accessory	*Body-worn SAR per KDB Publication 648474 D04*
Hotspot (DSI = 0)	_ DUT Configuration is Folder Open _ Device transmits in hotspot mode near body _ Hotspot Mode Active	*Hotspot SAR per KDB Publication 941225 D06*
Phablet (DSI = 0)	_ DUT Configuration is Folder Open _ Device is held to hand	*Phablet SAR per KDB Publication 648474 D04 & KDB Publication 616217 D04*

2.2. SAR design Target

SAR_*design_target* is determined by ensuring that it is less than FCC SAR limit after accounting for total device designed related uncertainties specified by the manufacturer.

Table 2-2

SAR_*design_target*			
$SAR\_design\_target < SAR\_regulatory\_limit \times 10^{\frac{-Total\ Uncertainty}{10}}$			
1g SAR		10g SAR	
Total Uncertainty	1.0 dB	*Total Uncertainty*	1.0 dB
SAR_regulatory_limit	1.6 W/kg	*SAR_regulatory_limit*	4.0 W/kg
SAR_design_target	1.0 W/kg	*SAR_design_target*	2.5 W/kg

2.3. SAR Char

SAR test results corresponding to Pmax for each antenna/technology/band/DSI can be found in Part 1 report and SAR results section in this report.

P_{limit} is calculated by linearly scaling with the measured SAR at the P_{part0} to correspond to the SAR_*design_target*. When P_{limit} < P_{max}, P_{part0} was used as P_{limit} in the Smart Transmit EFS. When P_{limit} > P_{max} and P_{part0}=P_{max}, calculated P_{limit} was used in the Smart Transmit EFS. All reported SAR obtained from the P_{part0} SAR tests was less than SAR_*Design_target*+ 1 dB Uncertainty. The final Plimit determination for each exposure scenario corresponding to SAR_design_target is shown in the below table.

Table 2-3

Device State Index (DSI)	Plimit Determination Scenarios
0	The worst-case SAR exposure for Folder Open is determined as maximum SAR normalized to the limit (i.e. lowest Plimit) among: 1. Body-worn SAR 2. Hotspot SAR 3. Phablet SAR

Notes:

- When P_{max} < P_{limit} EFS, the DUT will operate at a power level up to P_{max}
- All P_{limit} EFS and maximum tune up output power P_{max} levels entered in below Table correspond to average power levels after accounting for duty cycle in the case of TDD, GMSK, or OFDM modulation schemes (e.g. GSM, LTE TDD, NTN and WLAN/BT).
- Maximum tune up output power Pmax is used to configure EUT during RF tune up procedure. The maximum allowed output power is equal to maximum Tune up output power + 1dB device design uncertainty.
- All MIMO P_{max} and P_{limit} are defined per antenna chain
- Please refer to Change description in the filing for Band/Mode/Exposure Conditions affected in this Class II Permissive change.

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Table 2-4

Band/Mode	Antenna	Antenna Group	Exposure Scenario		Folder Open Body-worn/ Hotspot/ Phablet
			Maximum Tune-Up Output Power		DSI 0
			Pmax Burst (dBm)	Pmax Frame Avg (dBm)	Plimit (dBm)
6 GHz WIFI	E	AG1	16.0	16.0	9.0
6 GHz WIFI	F	AG1	16.0	16.0	9.0
6 GHz WIFI	MIMO (F&E)	AG1	16.0	16.0	9.0

3. Equipment List

Manufacturer	Model	Description	Serial Number	Calibration Date	Calibration Due	CBT
Amplifier Research	15S4G8AM1	RF Broadband Amplifier (4 - 8 GHz)	554497	-	-	✓
Rohde & Schwarz	SMCV100B	R&S SMCV100B Vector Signal Generator (VSG)	103882	12/30/25	12/30/27	-
SPEAG	Powersource1	Signal Generator	4341	1/6/26	1/6/27	-
Anritsu	MA24118A	Microwave USB Power Sensor (10MHz - 18 GHz)	2123431	1/22/26	1/22/27	-
Anritsu	MA24118A	Microwave USB Power Sensor (10MHz - 18 GHz)	2123500	1/22/26	1/22/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114184	3/12/26	3/12/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114183	3/12/26	3/12/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114343	4/1/26	4/1/27	-
Anritsu	S820E	Vector Network Analyzer	2348026	1/13/26	1/13/28	-
Control Company	4040	Ambient Thermometer	250440199	7/17/25	7/17/27	-
Control Company	4352	Long Stem Liquid Thermometer	250257665	4/23/25	4/23/27	-
Micro-Coax	UFB205A-0-0240-30x30	SMA M-F RF test Cable (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-N20W20+	20dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-N20W20+	20dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-S3W2+	3dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-S3W2+	3dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3318	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3335	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3329	-	-	✓
Mini-Circuits	NF-SF50+	RF Adapter N Male to SMA Female (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	VLF-8400+	Coaxial Low Pass Filter (DC - 8.4 GHz)	-	-	-	✓
Narda	24785-20	20 dB SMA Fixed Attenuator (DC - 4.0 GHz)	-	-	-	✓
Narda	4226-20 (26733)	20 dB SMA Directional Coupler (0.5 - 18 GHz)	201	-	-	✓
Mitutoyo	CD-4”AX	Digital Caliper	B23243217	8/28/25	8/28/27	-
SPEAG	DAK-3.5	DAK-3.5 Dielectric Probe	1349	8/5/25	8/5/26	-
SPEAG	10 GHz System Verification Source	10 GHz System Verification Source	1074	9/15/25	9/15/26	-
SPEAG	EUmmWV4	mmWave Measurement Probe	9690	9/17/25	9/17/26	-
SPEAG	D6.5GHzV2	6.5GHz System Validation Dipole	1104	10/11/24	10/11/26	-
SPEAG	DAE4ip	Data Acquisition Electronics with Integ. Power	1838	7/30/25	7/30/26	-
SPEAG	DAE4ip	Data Acquisition Electronics with Integ. Power	1905	5/8/26	5/8/27	-
SPEAG	EX3DV4	SAR Measurement Probe	7857	8/8/25	8/8/26	-
SPEAG	SE UMS 171 E	MAIA Modulation and Interference Analyzer	1814	-	-	-
SPEAG	SE UMS 176 C	ANT Wideband Communication Antenna	1579	-	-	-

✓Note: Components calibrated before testing. Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator, power sensor, or VNA) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.